

# **IGBT Chopper Module**

Replaces issue March 2002, version DS5491-2.0

DS5491-3.1 Octtober 2002

### **FEATURES**

- 10µs Short Circuit Withstand
- High Thermal Cycling Capability
- Non Punch Through Silicon
- Isolated MMC Base with AIN Substrates

### **APPLICATIONS**

- Choppers
- Motor Controllers
- Traction Drives

The Powerline range of modules includes half bridge, chopper, dual, single and bi-directional switch configurations covering voltages from 600V to 3300V and currents up to 2400A.

The DIM600DCM17-A000 is a 1700V, n channel enhancement mode insulated gate bipolar transistor (IGBT) chopper module. The IGBT has a wide reverse bias safe operating area (RBSOA) plus full 10 $\mu$ s short circuit withstand. This module is optimised for traction drives and other applications requiring high thermal cycling capability.

The module incorporates an electrically isolated base plate and low inductance construction enabling circuit designers to optimise circuit layouts and utilise grounded heat sinks for safety.

### ORDERING INFORMATION

Order As:

### DIM600DCM17-A000

Note: When ordering, please use the whole part number.

### **KEY PARAMETERS**

| V <sub>CES</sub>                         |       | 1700V |
|--|-------|-------|
|  | (typ) | 2.7V  |
| V <sub>CE(sat)</sub> *<br>I <sub>C</sub> | (max) | 600A  |
| I <sub>C(PK)</sub>                       | (max) | 1200A |

\*(measured at the power busbars and not the auxiliary terminals)

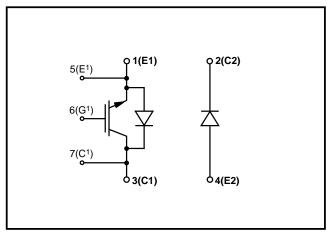


Fig. 1 Chopper circuit diagram

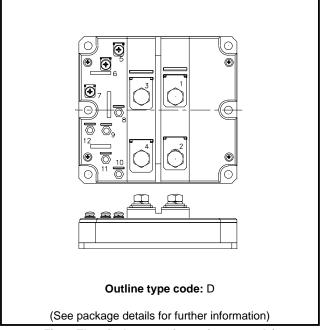


Fig. 2 Electrical connections - (not to scale)

Caution: This device is sensitive to electrostatic discharge. Users should follow ESD handling procedures.

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## **ABSOLUTE MAXIMUM RATINGS - PER ARM**

Stresses above those listed under 'Absolute Maximum Ratings' may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed. Exposure to Absolute Maximum Ratings may affect device reliability.

T<sub>case</sub> = 25°C unless stated otherwise

| Symbol             | Parameter                                | Test Conditions   | Max. | Units             |
|--------------------|--|---|------|-------------------|
| V <sub>CES</sub>   | Collector-emitter voltage                | $V_{GE} = 0V$   | 1700 | V                 |
| V <sub>GES</sub>   | Gate-emitter voltage                     | -   | ±20  | V                 |
| I <sub>c</sub>     | Continuous collector current             | $T_{case} = 75^{\circ}C$  | 600  | А                 |
| I <sub>C(PK)</sub> | Peak collector current                   | 1ms, T <sub>case</sub> = 110°C                                    | 1200 | А                 |
| P <sub>max</sub>   | Max. transistor power dissipation        | $T_{case} = 25^{\circ}C, T_{j} = 150^{\circ}C$                    | 5200 | W                 |
| l²t                | Diode I <sup>2</sup> t value (IGBT arm)  | $V_R = 0, t_p = 10 \text{ms}, T_{v_j} = 125^{\circ} \text{C}$     | 120  | kA2s              |
|                    | Diode I <sup>2</sup> t value (Diode arm) |   | 120  | kA <sup>2</sup> s |
| $V_{isol}$         | Isolation voltage - per module           | Commoned terminals to base plate. AC RMS, 1 min, 50Hz             | 4000 | V                 |
| $Q_{_{PD}}$        | Partial discharge - per module           | IEC1287. V <sub>1</sub> = 1800V, V <sub>2</sub> = 1300V, 50Hz RMS | 10   | рС                |



# THERMAL AND MECHANICAL RATINGS

Internal insulation material: AIN
Baseplate material: AISiC
Creepage distance: 20mm
Clearance: 10mm
CTI (Critical Tracking Index): 175

| Symbol               | Parameter                                 | Test Conditions             | Min. | Тур. | Max. | Units |
|----------------------|---|-----------------------------|------|------|------|-------|
| R <sub>th(j-c)</sub> | Thermal resistance - transistor (per arm) | Continuous dissipation -    | -    | -    | 27   | °C/kW |
|                      |   | junction to case            |      |      |      |       |
| R <sub>th(j-c)</sub> | Thermal resistance - diode (IGBT arm)     | Continuous dissipation -    | -    | -    | 40   | °C/kW |
|                      | Thermal resistance - diode (Diode arm)    | junction to case            | -    | -    | 40   | °C/kW |
| R <sub>th(c-h)</sub> | Thermal resistance - case to heatsink     | Mounting torque 5Nm         | -    | -    | 8    | °C/kW |
|                      | (per module)                              | (with mounting grease)      |      |      |      |       |
| T <sub>j</sub>       | Junction temperature                      | Transistor                  | -    | -    | 150  | °C    |
|                      |   | Diode                       | -    | -    | 125  | °C    |
| T <sub>stg</sub>     | Storage temperature range                 | -                           | -40  | -    | 125  | °C    |
| -                    | Screw torque                              | Mounting - M6               | -    | -    | 5    | Nm    |
|                      |   | Electrical connections - M4 | -    | -    | 2    | Nm    |
|                      |   | Electrical connections - M8 | -    | -    | 10   | Nm    |

Caution: This device is sensitive to electrostatic discharge. Users should follow ESD handling procedures.



# **ELECTRICAL CHARACTERISTICS**

 $T_{case}$  = 25°C unless stated otherwise.

| Symbol                      | Parameter                                | Test Conditions  | Min. | Тур. | Max. | Units |
|-----------------------------|--|--|------|------|------|-------|
| I <sub>CES</sub>            | Collector cut-off current                | $V_{GE} = 0V$ , $V_{CE} = V_{CES}$   | -    | -    | 1    | mA    |
|                             |  | V <sub>GE</sub> = 0V, V <sub>CE</sub> = V <sub>CES</sub> , T <sub>case</sub> = 125°C | -    | -    | 20   | mA    |
| I <sub>GES</sub>            | Gate leakage current                     | $V_{GE} = \pm 20V, V_{CE} = 0V$  | -    | -    | 4    | μА    |
| V <sub>GE(TH)</sub>         | Gate threshold voltage                   | $I_{\rm C}$ = 30mA, $V_{\rm GE}$ = $V_{\rm CE}$                                      | 4.5  | 5.5  | 6.5  | V     |
| V <sub>CE(sat)</sub> †      | Collector-emitter saturation voltage     | V <sub>GE</sub> = 15V, I <sub>C</sub> = 600A   | -    | 2.7  | 3.2  | V     |
|                             |  | V <sub>GE</sub> = 15V, I <sub>C</sub> = 600A, , T <sub>case</sub> = 125°C            | -    | 3.4  | 4.0  | V     |
| I <sub>F</sub>              | Diode forward current                    | DC   | -    | -    | 600  | А     |
| I <sub>FM</sub>             | Diode maximum forward current            | t <sub>p</sub> = 1ms   | -    | -    | 1200 | А     |
| V <sub>F</sub> <sup>†</sup> | Diode forward voltage (IGBT arm)         | I <sub>F</sub> = 600A  | -    | 2.0  | 2.3  | V     |
|                             | Diode forward voltage (Diode arm)        |  | -    | 2.0  | 2.3  | V     |
|                             | Diode forward voltage (IGBT arm)         | I <sub>F</sub> = 600A, T <sub>case</sub> = 125°C                                     | -    | 2.1  | 2.4  | V     |
|                             | Diode forward voltage (Diode arm)        |  | -    | 2.1  | 2.4  | V     |
| C <sub>ies</sub>            | Input capacitance                        | V <sub>CE</sub> = 25V, V <sub>GE</sub> = 0V, f = 1MHz                                | -    | 45   | -    | nF    |
| C <sub>res</sub>            | Reverse transfer capacitance             | V <sub>CE</sub> = 25V, V <sub>GE</sub> = 0V, f = 1MHz                                | -    | 3.8  | -    | nF    |
| L <sub>M</sub>              | Module inductance - per arm              | -  | -    | 20   | -    | nH    |
| R <sub>INT</sub>            | Internal transistor resistance - per arm | -  | -    | 0.27 | -    | mΩ    |
| SC <sub>Data</sub>          | Short circuit. I <sub>sc</sub>           | $T_j = 125^{\circ}C, V_{CC} = 1000V,$ $I_1$  |      | 2780 | -    | А     |
|                             |  | $t_p \le 10 \mu s$ , $V_{CE(max)} = V_{CES} - L^*$ . di/dt $I_2$                     |      | 2400 | -    | А     |
|                             |  | IEC 60747-9  |      |      |      |       |

#### Note:

<sup>&</sup>lt;sup>†</sup> Measured at the power busbars and not the auxiliary terminals)

 $<sup>^{\</sup>star}$  L is the circuit inductance +  $\rm L_{M}$ 



# **ELECTRICAL CHARACTERISTICS**

# $T_{\text{case}} = 25^{\circ}\text{C}$ unless stated otherwise

| Symbol              | Parameter                      |           | Test Conditions                                    | Min. | Тур. | Max. | Units |
|---------------------|--------------------------------|-----------|--|------|------|------|-------|
| t <sub>d(off)</sub> | Turn-off delay time            |           | I <sub>C</sub> = 600A                              | -    | 1200 | -    | ns    |
| t <sub>f</sub>      | Fall time                      |           | $V_{GE} = \pm 15V$                                 | -    | 140  | -    | ns    |
| E <sub>OFF</sub>    | Turn-off energy loss           |           | V <sub>CE</sub> = 900V                             | -    | 190  | -    | mJ    |
| t <sub>d(on)</sub>  | Turn-on delay time             |           | $R_{\text{G(ON)}} = R_{\text{G(OFF)}} = 3.3\Omega$ | -    | 250  | -    | ns    |
| t,                  | Rise time                      |           | L ~ 100nH  | -    | 250  | -    | ns    |
| E <sub>on</sub>     | Turn-on energy loss            |           |  | -    | 220  | -    | mJ    |
| $Q_g$               | Gate charge                    |           |  | -    | 6.8  | -    | μС    |
| Q <sub>rr</sub>     | Diode reverse recovery charge  | Diode arm | I <sub>F</sub> = 600A,                             | -    | 370  | -    | μС    |
|                     |                                | IGBT arm  | $V_R = 50\% V_{CES}$                               | -    | 150  | -    | μС    |
| I <sub>rr</sub>     | Diode reverse recovery current | Diode arm | $dI_F/dt = 3000A/\mu s$                            | -    | 800  | -    | А     |
|                     |                                | IGBT arm  |  | -    | 350  | -    | Α     |
| E <sub>rec</sub>    | Diode reverse recovery energy  | Diode arm |  | -    | 250  | -    | mJ    |
|                     |                                | IGBT arm  |  | -    | 100  | -    | mJ    |



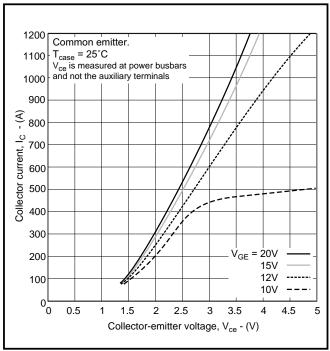
## **ELECTRICAL CHARACTERISTICS**

T<sub>case</sub> = 125°C unless stated otherwise

| Symbol              | Parameter                      |           | Test Conditions                      | Min. | Тур. | Max. | Units |
|---------------------|--------------------------------|-----------|--------------------------------------|------|------|------|-------|
| t <sub>d(off)</sub> | Turn-off delay time            |           | I <sub>C</sub> = 600A                | -    | 1500 | -    | ns    |
| t <sub>f</sub>      | Fall time                      |           | $V_{GE} = \pm 15V$                   | -    | 170  | -    | ns    |
| E <sub>OFF</sub>    | Turn-off energy loss           |           | V <sub>CE</sub> = 900V               | -    | 270  | -    | mJ    |
| t <sub>d(on)</sub>  | Turn-on delay time             |           | $R_{G(ON)} = R_{G(OFF)} = 3.3\Omega$ | -    | 400  | -    | ns    |
| t,                  | Rise time                      |           | L ~ 100nH                            | -    | 250  | -    | ns    |
| E <sub>on</sub>     | Turn-on energy loss            |           |                                      | -    | 350  | -    | mJ    |
| Q <sub>rr</sub>     | Diode reverse recovery charge  | Diode arm | I <sub>F</sub> = 600A,               | -    | 650  | -    | μС    |
|                     |                                | IGBT arm  | $V_R = 50\% V_{CES}$                 | -    | 250  | -    | μС    |
| I <sub>rr</sub>     | Diode reverse recovery current | Diode arm | $dI_{\rm F}/dt = 3000A/\mu s$        | -    | 900  | -    | А     |
|                     |                                | IGBT arm  |                                      | -    | 400  | -    | А     |
| E <sub>rec</sub>    | Diode reverse recovery energy  | Diode arm |                                      | -    | 380  | -    | mJ    |
|                     |                                | IGBT arm  |                                      | -    | 150  | -    | mJ    |



### TYPICAL CHARACTERISTICS



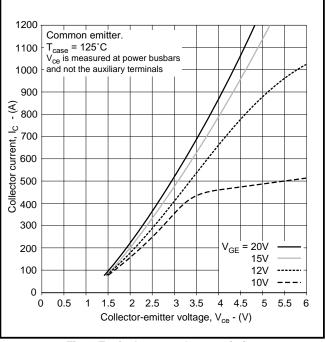
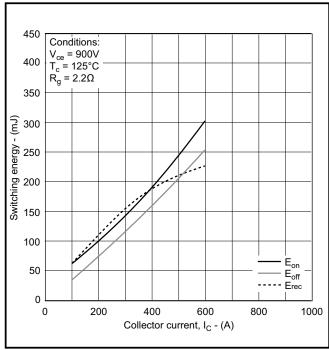
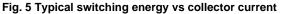


Fig. 3 Typical output characteristics

Fig. 4 Typical output characteristics





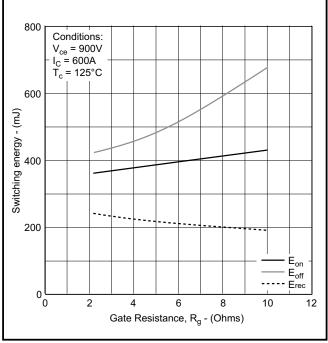
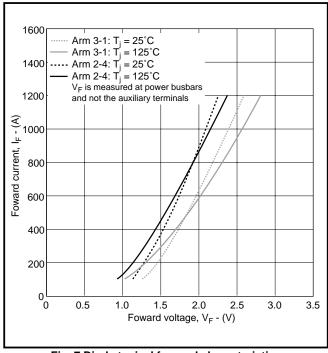


Fig. 6 Typical switching energy vs gate resistance

Caution: This device is sensitive to electrostatic discharge. Users should follow ESD handling procedures.





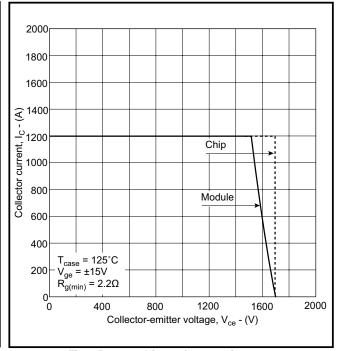
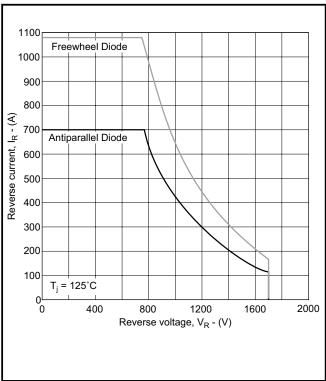
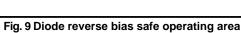


Fig. 7 Diode typical forward characteristics

Fig. 8 Reverse bias safe operating area





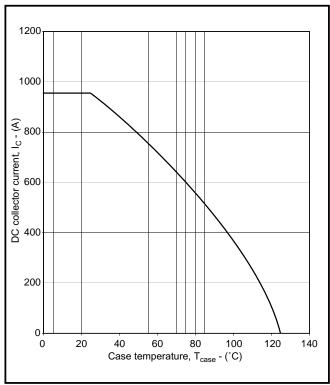


Fig. 10 DC current rating vs case temperature

Caution: This device is sensitive to electrostatic discharge. Users should follow ESD handling procedures.

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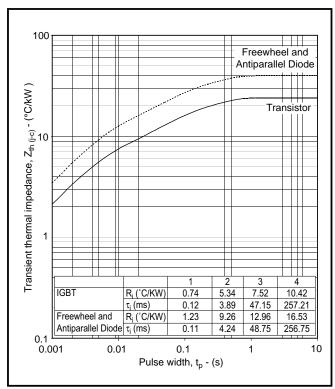
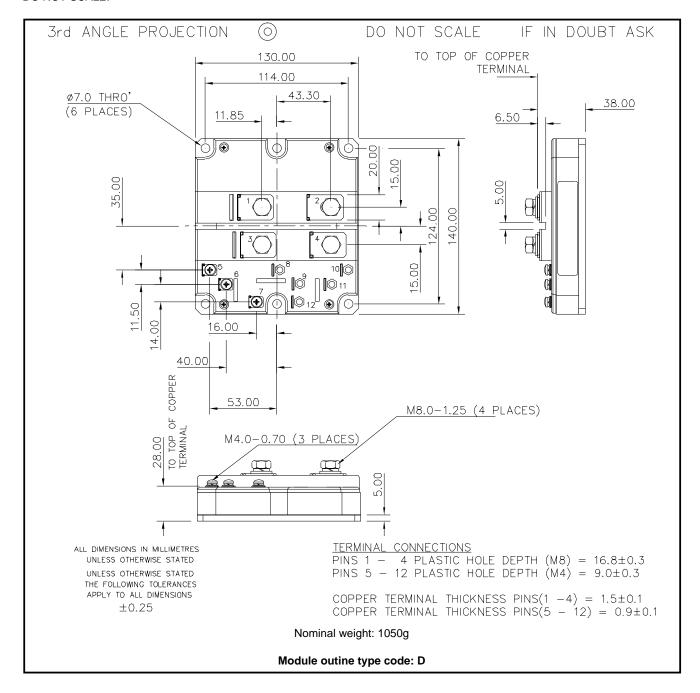


Fig. 11 Transient thermal impedance



### **PACKAGE DETAILS**

For further package information, please visit our website or contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.



Caution: This device is sensitive to electrostatic discharge. Users should follow ESD handling procedures.

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The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

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